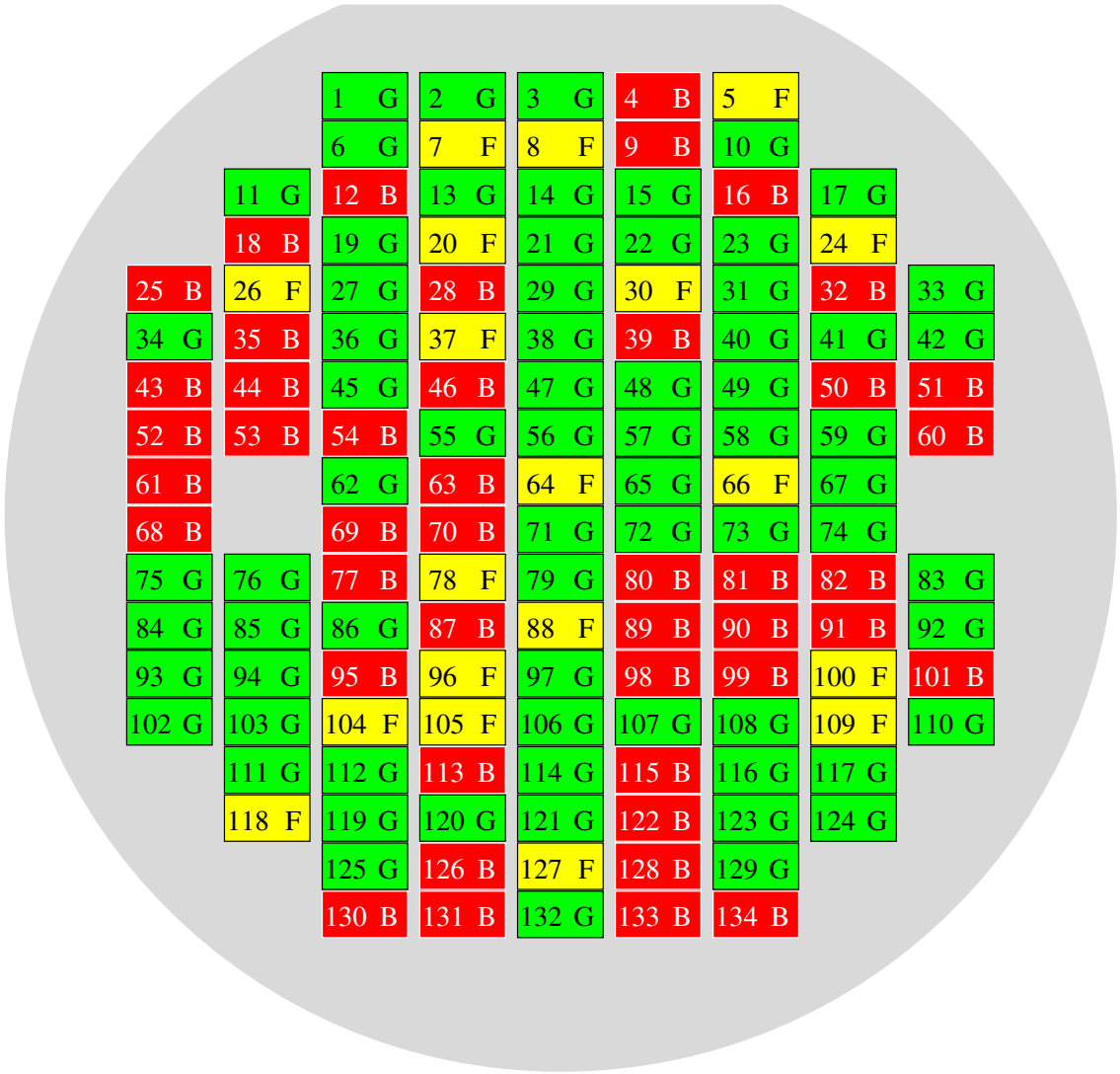
Die quality map for wafer 179 s/n: Y21316-09-09

Date: 07/09/99



# B	Bad die
# F	Fair die
# G	Good die
# N	No info
# *	Manually tagged